

[54] X-RAY INSPECTION CABINET
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[**] Term: 14 Years
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 [52] U.S. Cl. D24/02; D24/1.1
 [58] Field of Search 312/209; 250/475.1;
 40/361; D24/2, 1.1; D16/14, 24

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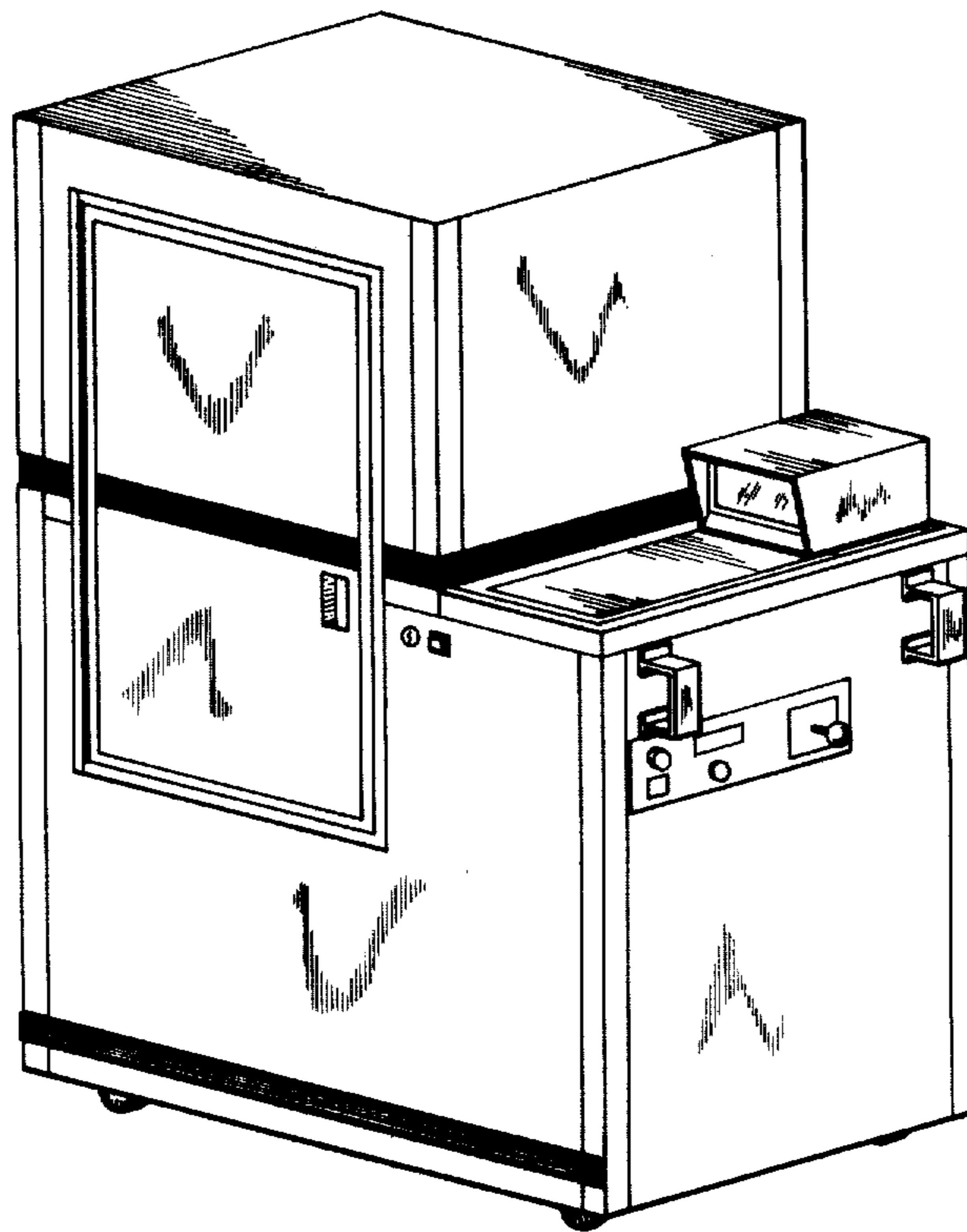
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 Attorney, Agent, or Firm—Paul R. Miller

[57] CLAIM

The ornamental design for an x-ray inspection cabinet, as shown and described.

DESCRIPTION

FIG. 1 is a front perspective view of an x-ray inspection cabinet showing my new design;
 FIG. 2 is a front elevational view thereof;
 FIG. 3 is a right-side elevational view of a modified embodiment thereof;
 FIG. 4 is a rear elevational view thereof; and
 FIG. 5 is a right-side elevational view thereof.



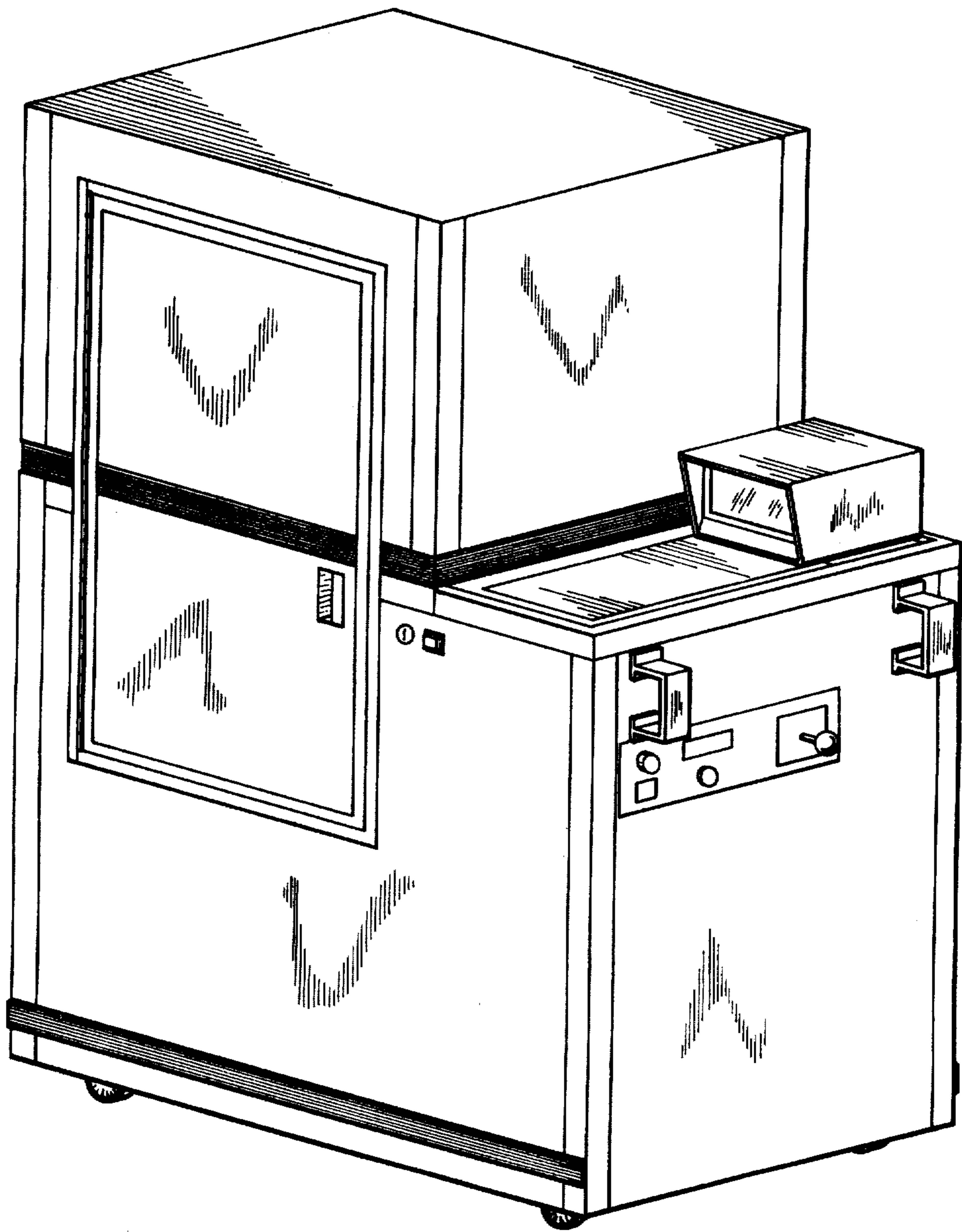


Fig. 1

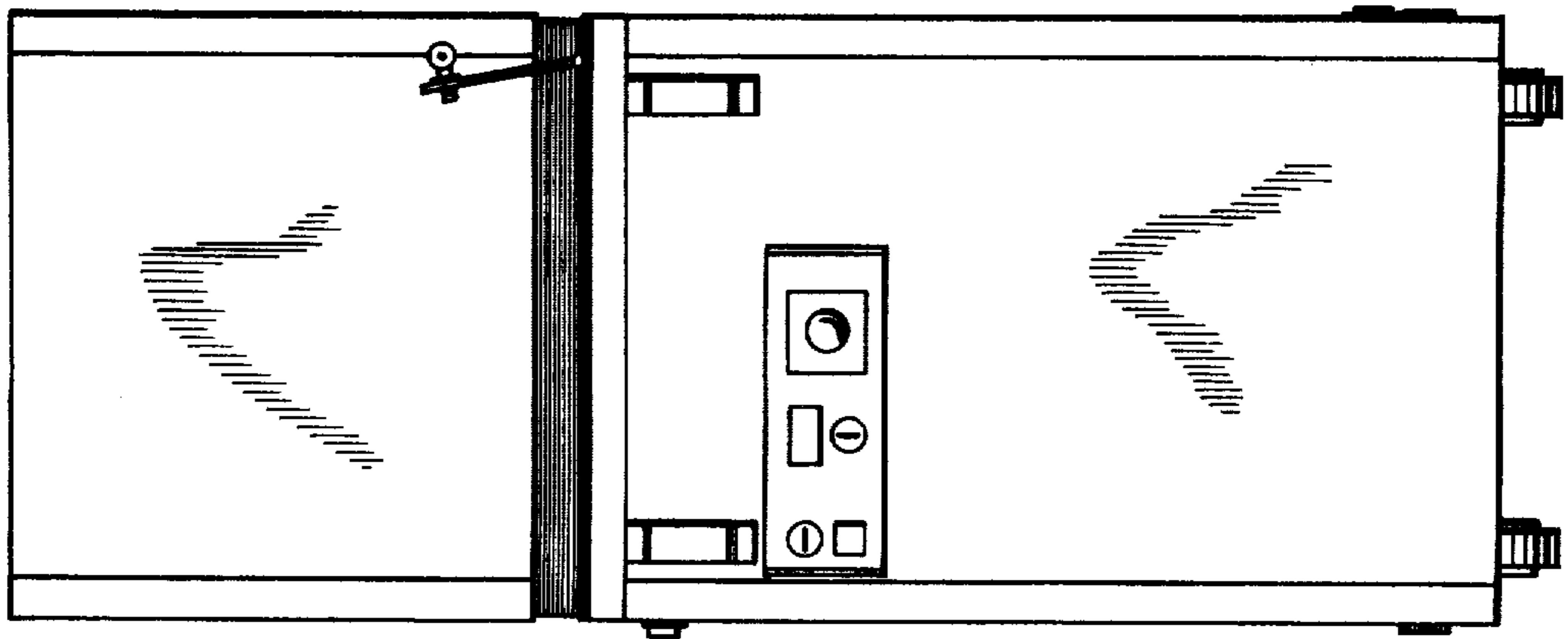


Fig. 3

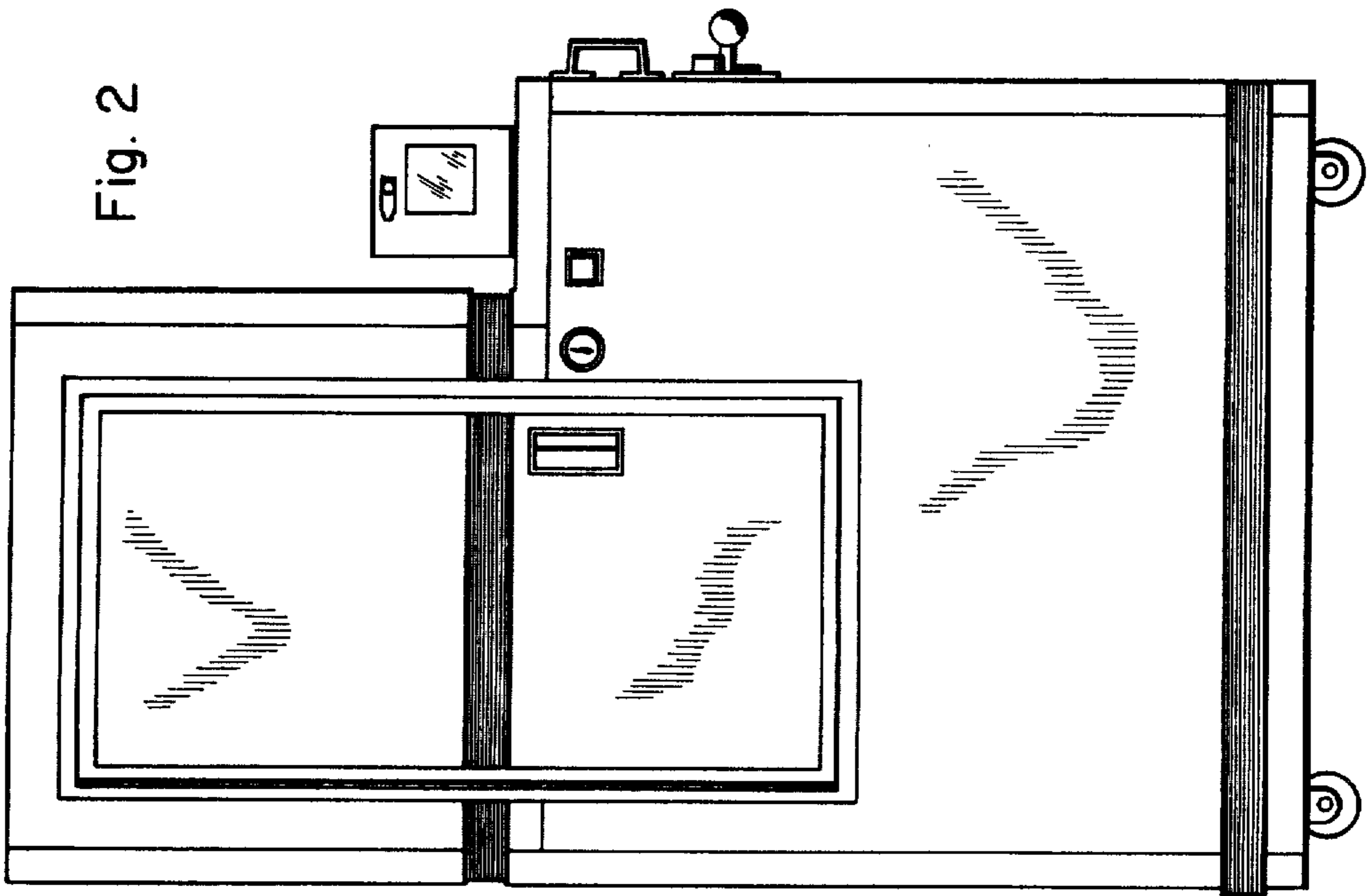


Fig. 2

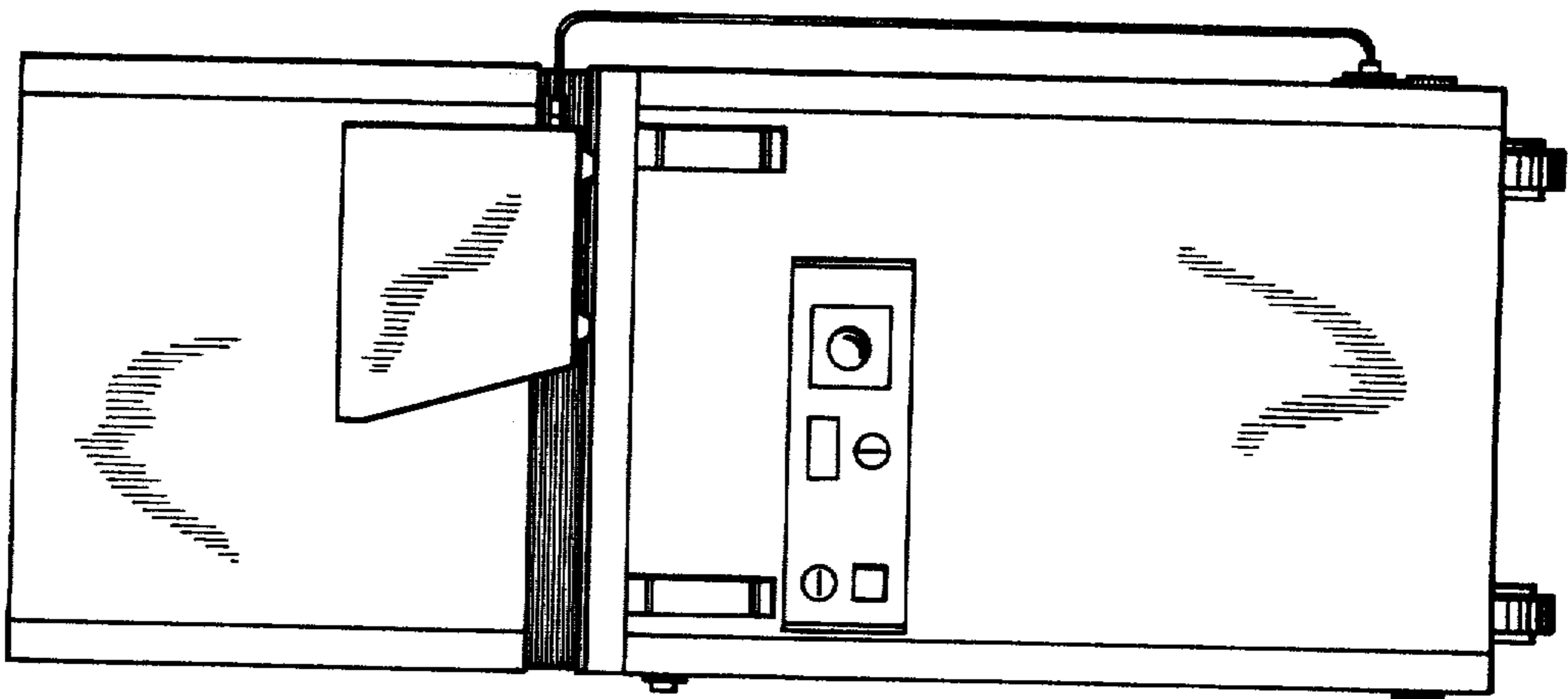


Fig. 5

Fig. 4

